



**DIODES, RECTIFIER,
BASED ON TYPES 1N4942, 1N4944, 1N4946,
1N4947 AND 1N4948
ESCC Detail Specification No. 5103/008**

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	ESCC Detail Specification		PAGE ii ISSUE 1
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Pages 1 to 16

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1N4947 AND 1N4948
ESA/SCC Detail Specification No. 5103/008



**space components
coordination group**

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DOCUMENTATION CHANGE NOTICE

Rev. Letter	Rev. Date	Reference	CHANGE Item	Approved DCR No.
'A'	June '81	This issue incorporates all modifications agreed on the basis of Policy DCR 21016 for adaptation to new qualification requirements.		None None 21019 23063 21019 23063 23063
		P1. Cover page P2. DCN P4. Reference to Appendices P6. Table 1(a) : Addition of lead materials P9. Para. 4.1 : Reference to Appendices P10. Para. 4.3.3 : Modification of applied force to include value in pounds Para. 4.4.2 : Modification of lead material		
'B'	July '93	P1. Cover Page P2. DCN P9. Para. 4.2.2 : PIND deviation amended		None None 21043
		This document has been transferred from hardcopy to electronic format. The content is unchanged but minor differences in presentation exist.		
'C'	July '96	P1. Cover Page P2. DCN P3. T of C : Para. 1.7 entry added P5. Para. 1.7 : Paragraph added P6. Table 1(a) : Column 7 heading amended : Lead Material coded to "01" and "A4" respectively P9. Para. 2 : Item (c) deleted P10. Para. 4.4.2 : Text amended		None None 21083 21083 21025 21025 21025 21025



TABLE OF CONTENTS

	<u>Page</u>
1. <u>GENERAL</u>	5
1.1 Scope	5
1.2 Component Type Variants	5
1.3 Maximum Ratings	5
1.4 Parameter Derating Information	5
1.5 Physical Dimensions	5
1.6 Functional Diagram	5
1.7 High Temperature Test Precautions	5
2. <u>APPLICABLE DOCUMENTS</u>	9
3. <u>TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS</u>	9
4. <u>REQUIREMENTS</u>	9
4.1 General	9
4.2 Deviations from Generic Specification	9
4.2.1 Deviations from Special In-process Controls	9
4.2.2 Deviations from Final Production Tests (Chart II)	9
4.2.3 Deviations from Burn-in and Electrical Measurements (Chart III)	9
4.2.4 Deviations from Qualification Tests (Chart IV)	9
4.2.5 Deviations from Lot Acceptance Tests (Chart V)	9
4.3 Mechanical Requirements	10
4.3.1 Dimension Check	10
4.3.2 Weight	10
4.3.3 Terminal Strength	10
4.4 Materials and Finishes	10
4.4.1 Case	10
4.4.2 Lead Material and Finish	10
4.5 Marking	11
4.5.1 General	11
4.5.2 Lead Identification	11
4.5.3 The SCC Component Number	11
4.5.4 Traceability Information	11
4.5.5 Marking of Small Components	11



	<u>Page</u>
4.6 Electrical Measurements	12
4.6.1 Electrical Measurements at Room Temperature	12
4.6.2 Electrical Measurements at High and Low Temperatures	12
4.6.3 Circuits for Electrical Measurements	12
4.7 Burn-in Tests	12
4.7.1 Parameter Drift Values	12
4.7.2 Conditions for Burn-in	12
4.7.3 Electrical Circuits for Burn-in	12
4.8 Environmental and Endurance Tests	15
4.8.1 Electrical Measurements on Completion of Environmental Tests	15
4.8.2 Electrical Measurements at Intermediate Points and on Completion of Endurance Tests	15
4.8.3 Conditions for Operating Life Tests (Part of Endurance Testing)	15
4.8.4 Electrical Circuits for Operating Life Tests	15
4.8.5 Conditions for High Temperature Storage Test (Part of Endurance Testing)	15

TABLES

1(a) Type Variants	6
1(b) Maximum Ratings	6
2 Electrical Measurements at Room Temperature (d.c. and a.c. Parameters)	13
3 Electrical Measurements at High and Low Temperatures	14
4 Parameter Drift Values	14
5 Conditions for Burn-in	14
6 Electrical Measurements at Intermediate Points and on Completion of Endurance Testing	16

FIGURES

1 Parameter Derating Information	7
2 Physical Dimensions	8
3 Functional Diagram	8
4 Test Circuits	13
5 Electrical Circuit for Burn-in	14

APPENDICES (Applicable to specific Manufacturers only)

None.



1. **GENERAL**

1.1 **SCOPE**

This specification details the ratings, physical and electrical characteristics, test and inspection data for Diodes, Rectifier, based on Types 1N4942, 1N4944, 1N4946, 1N4947 and 1N4948.

It shall be read in conjunction with ESA/SCC Generic Specification No. 5000, the requirements of which are supplemented herein.

1.2 **COMPONENT TYPE VARIANTS**

Variants of the basic diodes specified herein, which are also covered by this specification, are listed in Table 1(a).

1.3 **MAXIMUM RATINGS**

The maximum ratings, which shall not be exceeded at any time during use or storage, applicable to the diodes specified herein, are scheduled in Table 1(b).

1.4 **PARAMETER DERATING INFORMATION**

The derating information applicable to the diodes specified herein is shown in Figure 1.

1.5 **PHYSICAL DIMENSIONS**

The physical dimensions of the diodes specified herein are shown in Figure 2.

1.6 **FUNCTIONAL DIAGRAM**

The functional diagram, showing lead identification, of the diodes specified herein, is shown in Figure 3.

1.7 **HIGH TEMPERATURE TEST PRECAUTIONS**

For tin-lead plated or solder-dipped lead finish, all tests to be performed at a temperature that exceeds +125°C shall be carried out in a 100% inert atmosphere.



TABLE 1(a) - TYPE VARIANTS

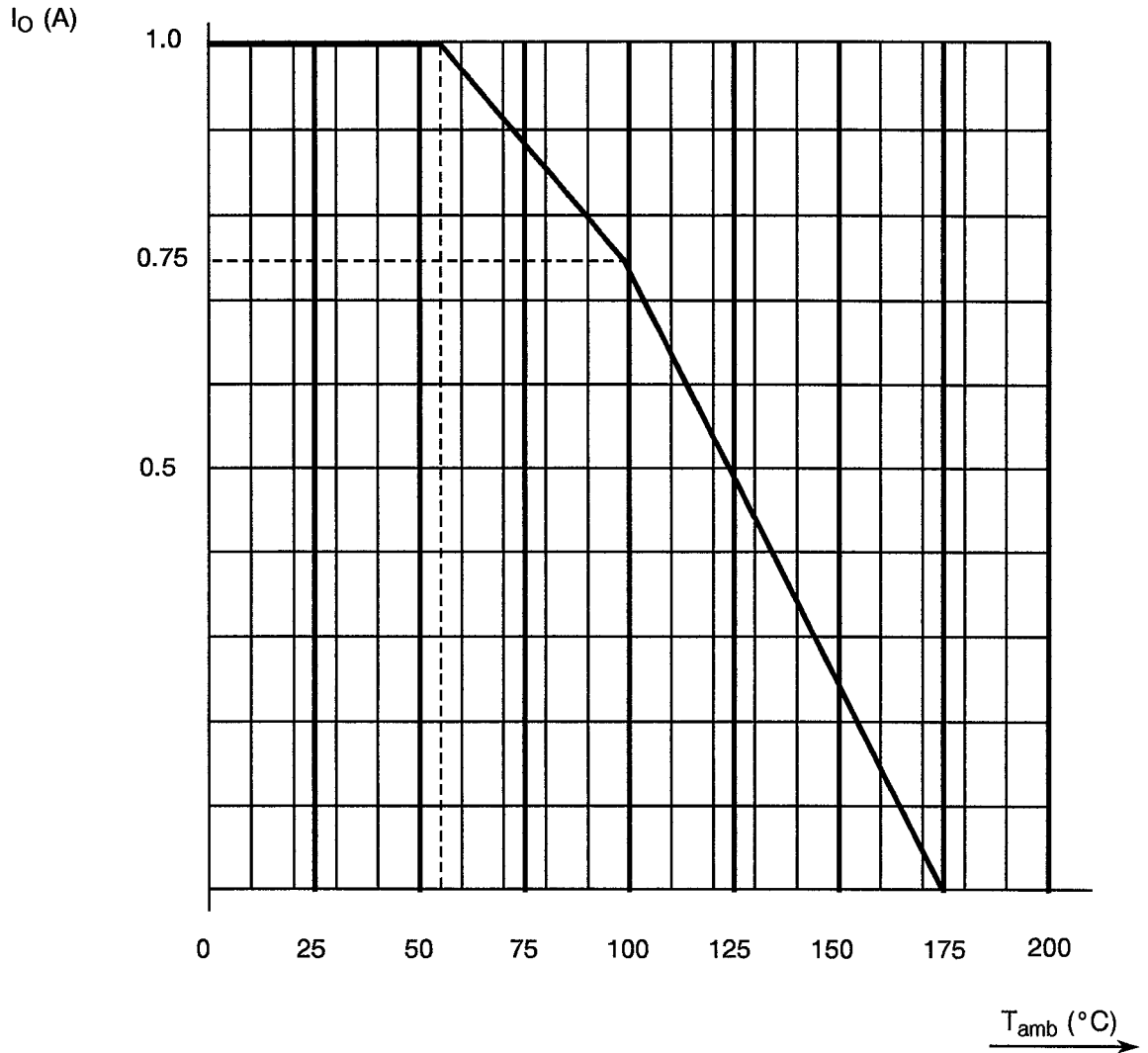
(1) Type Variant	(2) Similar to Type	(3) V_R (V)	(4) t_{rr} (ns)	(5) V_{BR} (V)	(6) C_j (pF)	(7) Lead Material and Finish
01	1N4942	200	150	220	45	01
02	1N4944	400	150	440	35	01
03	1N4946	600	150	660	25	01
04	1N4947	800	250	880	20	01
05	1N4948	1000	500	1100	15	01
06	1N4942	200	150	220	45	A4
07	1N4944	400	150	440	35	A4
08	1N4946	600	150	660	25	A4
09	1N4947	800	250	880	20	A4
10	1N4948	1000	500	1100	15	A4

TABLE 1(b) - MAXIMUM RATINGS

No.	CHARACTERISTIC	SYMBOL	MAXIMUM RATING	UNIT	REMARKS
1	Reverse Voltage	V_R	See Table 1(a)	V	
2	Average Output Current	I_O	1.0	A	See Figure 1
3	Forward Surge Current	$I_{f(surge)}$	15	A	$t_p = 8.3ms$ $T_{amb} = +100^\circ C$
4	Forward Surge Current	$I_{f(surge)}$	30	A	$t_p = 10ms$ $T_Z = +25^\circ C$
5	Operating Temperature Range	T_{op}	-55 to +175	$^\circ C$	T_{amb}
6	Storage Temperature Range	T_{stg}	-65 to +175	$^\circ C$	
7	Soldering Temperature	T_{sol}	+260	$^\circ C$	Time: ≤ 10 seconds; Distance from case: $\geq 1.5mm$



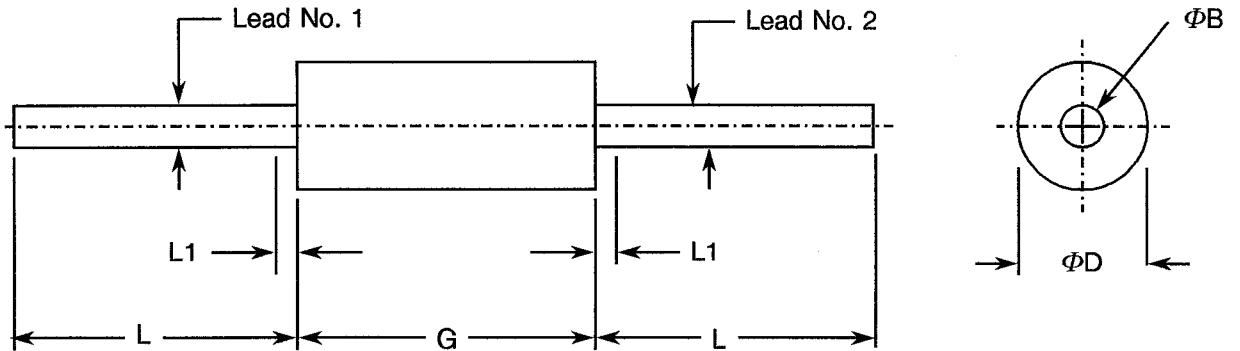
FIGURE 1 - PARAMETER DERATING INFORMATION



Average Output Current versus Temperature



FIGURE 2 - PHYSICAL DIMENSIONS



SYMBOL	INCHES		MILLIMETRES		NOTES
	MIN.	MAX.	MIN.	MAX.	
ΦB	0.027	0.035	0.69	0.88	1
ΦD	0.080	0.150	2.04	3.81	
G	0.225	0.300	5.72	7.62	
L	1.000	1.625	25.40	41.27	
L1	-	0.050	-	1.27	4

NOTES

1. Two leads.
2. Metric equivalents (to the nearest 0.01mm) are given for general information only and are based upon 1 inch = 25.4mm.
3. Leads and metallic end seals shall be electrically insulated from the case.
4. Within this zone the diameter may vary to allow for lead finishes and irregularities.



FIGURE 3 - FUNCTIONAL DIAGRAM



1. Anode
2. Cathode

NOTES

1. The cathode end shall be marked with a coloured ring.

		<p style="text-align: center;">ESA/SCC Detail Specification No. 5103/008</p>	<p style="text-align: center;">Rev. 'C'</p>	<p>PAGE 9 ISSUE 2</p>
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2. APPLICABLE DOCUMENTS

The following documents form part of this specification and shall be read in conjunction with it:

- (a) ESA/SCC Generic Specification No. 5000 for Discrete Semiconductors.
- (b) MIL-STD-750, Test Methods and Procedures for Semiconductor Devices.

3. TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS

For the purpose of this specification, the terms, definitions, abbreviations, symbols and units specified in ESA/SCC Basic Specification No. 21300 shall apply.

4. REQUIREMENTS

4.1 GENERAL

The complete requirements for procurement of the diodes specified herein are stated in this specification and ESA/SCC Generic Specification No. 5000 for Discrete Semiconductors. Deviations from the Generic Specification applicable to this specification only, are listed in Para. 4.2.

Deviations from the applicable Generic Specification and this Detail Specification, formally agreed with specific Manufacturers on the basis that the alternative requirements are equivalent to the ESA/SCC requirements and do not affect the components' reliability, are listed in the appendices attached to this specification.

4.2 DEVIATIONS FROM GENERIC SPECIFICATION

4.2.1 Deviations from Special In-process Controls

None.

4.2.2 Deviations from Final Production Tests (Chart II)

- (a) Para. 9.2.1, Bond Strength Test: Not applicable.
- (b) Para. 9.7, Particle Impact Noise Detection (PIND) Test: Not applicable.
- (c) Para. 9.5, Thermal Shock Test: To be performed according to MIL-STD-202, Test Method 107, Test Condition 'B'.

4.2.3 Deviations from Burn-in and Electrical Measurements (Chart III)

Subpara. 7.1.1(a): HTRB test shall not be performed.

4.2.4 Deviations from Qualification Tests (Chart IV)

- (a) Bond Strength Test (Subgroup III): Shall not be performed.

4.2.5 Deviations from Lot Acceptance Tests (Chart V)

None.

**SCC**ESA/SCC Detail Specification
No. 5103/008

Rev. 'C'

PAGE 10

ISSUE 2

4.3 MECHANICAL REQUIREMENTS

4.3.1 Dimension Check

The dimensions of the diodes specified herein shall be checked. They shall conform to those shown in Figure 2.

4.3.2 Weight

The maximum weight of the diodes specified herein shall be 1.1 grammes.

4.3.4 Terminal Strength

The requirements for terminal strength testing are specified in Section 9 of ESA/SCC Generic Specification No. 5000. The test conditions shall be as follows:-

Test Condition : 'A'.
Applied Force : 30 Newtons (5 pounds).
Duration : 15 seconds.

4.4 MATERIALS AND FINISHES

The materials and finishes shall be as specified herein. Where a definite material is not specified, a material which will enable the diodes specified herein to meet the performance requirements of this specification shall be used. Acceptance or approval of any constituent material does not guarantee acceptance of the finished product.

4.4.1 Case

Glass, hermetically sealed.

4.4.2 Lead Material and Finish

The lead material shall be either Type 'A' with Type '4' finish or Type 'O' with Type '1' finish in accordance with the requirements of ESA/SCC Basic Specification no. 23500. (See Table 1(a) for Type Variants).

4.5 MARKING

4.5.1 General

The marking of all components delivered to this specification shall be in accordance with the requirements of ESA/SCC Basic Specification No. 21700. Each component shall be marked in respect of:-

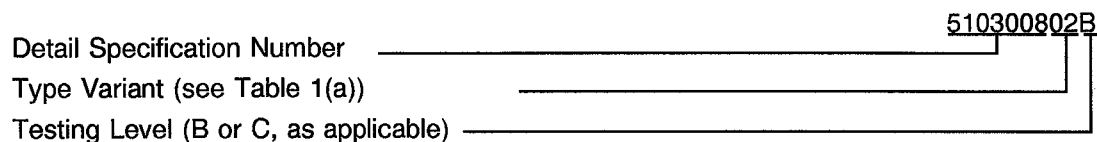
- (a) Lead Identification.
- (b) The SCC Component Number.
- (c) Traceability Information.

4.5.2 Lead Identification

Lead identification shall be as shown in Figures 2 and 3.

4.5.3 The SCC Component Number

Each component shall bear the SCC Component Number which shall be constituted and marked as follows:



4.5.4 Traceability Information

Each component shall be marked in respect of traceability information in accordance with the requirements of ESA/SCC Basic Specification No. 21700.

4.5.5 Marking of Small Components

When it is considered that the component is too small to accommodate the marking as specified above, as much as space permits shall be marked. The order of precedence shall be as follows:-

- (a) Lead Identification.
- (b) The SCC Component Number.
- (c) Traceability Information.

The marking information in full shall accompany each component in its primary package.



4.6 ELECTRICAL MEASUREMENTS

4.6.1 Electrical Measurements at Room Temperature

The parameters to be measured at room temperature are scheduled in Table 2. The measurements shall be performed at $T_{amb} = +22 \pm 3$ °C.

4.6.2 Electrical Measurements at High and Low Temperatures

The parameters to be measured at high and low temperatures are scheduled in Table 3.

4.6.3 Circuits for Electrical Measurements

Circuits for use in performing the electrical measurements listed in Tables 2 and 3 of this specification are shown in Figure 4.

4.7 BURN-IN TESTS

4.7.1 Parameter Drift Values

The parameter drift values applicable to burn-in are specified in Table 4 of this specification. Unless otherwise stated, the measurements shall be performed at $T_{amb} = +22 \pm 3$ °C. The parameter drift values (Δ) applicable to the parameters scheduled, shall not be exceeded. In addition to these drift value requirements, the appropriate limit value specified for a given parameter in Table 2 shall not be exceeded.

4.7.2 Conditions for Burn-in

The requirements for burn-in are specified in Section 7 of ESA/SCC Generic Specification No. 5000. The conditions for burn-in shall be as specified in Table 5 of this specification.

4.7.3 Electrical Circuits for Burn-in (Figure 5)

Not applicable.

**TABLE 2 - ELECTRICAL MEASUREMENTS AT ROOM TEMPERATURE
(d.c. PARAMETERS)**

No.	CHARACTERISTICS	SYMBOL	SPEC. AND/OR TEST METHOD	TEST CONDITION	LIMITS		UNIT
					MIN.	MAX.	
1	Reverse Current	I_R	MIL-STD-750 Method 4016	$V_R = (1) V$	-	1.0	μA
2	Forward voltage	V_F	MIL-STD-750 Method 4011	$I_F = 1.0A$	-	1.3	V

NOTES

1. See Column 3 of Table 1(a).

(a.c. PARAMETERS)

No.	CHARACTERISTICS	SYMBOL	SPEC. AND/OR TEST METHOD	TEST CONDITION	LIMITS		UNIT
					MIN.	MAX.	
1	Junction Capacitance	C_j	MIL-STD-750 Method 4001	$V_R = 12V$ $f = 1.0MHz$	-	(1)	pF
2	Reverse Recovery Time	t_{rr}	MIL-STD-750 Method 4031B	$I_F = 0.5A$ $I_R = 1.0A$ $R_L = 100\Omega$ $I_{RR} = 0.25A$	-	(2)	ns

NOTES

1. See Column 6 of Table 1(a).
1. See Column 4 of Table 1(a).

FIGURE 4 - TEST CIRCUITS

Not applicable.

**TABLE 3 - ELECTRICAL MEASUREMENTS AT HIGH AND LOW TEMPERATURES**

No.	CHARACTERISTICS	SYMBOL	SPEC. AND/OR TEST METHOD	TEST CONDITION	LIMITS		UNIT
					MIN.	MAX.	
1	Reverse Current	I_R	MIL-STD-750 Method 4016	$T_{amb} = +150^{\circ}C$ $V_R = (1) V$	-	200	μA

NOTES

- See Column 3 of Table 1(a).

TABLE 4 - PARAMETER DRIFT VALUES

No.	CHARACTERISTICS	SYMBOL	SPEC. AND/OR TEST METHOD	TEST CONDITION	CHANGE LIMITS	UNIT
1	Forward Voltage	V_F	MIL-STD-750 Method 4011	$I_F = 1.0A$	± 100	mV
2	Reverse Current	I_R	MIL-STD-750 Method 4016	$V_R = (1) V$	± 50 or (2) 100	nA %

NOTES

- See Column 3 of Table 1(a).
- Whichever is greater.

TABLE 5 - CONDITIONS FOR BURN-IN

No.	CHARACTERISTIC	SYMBOL	CONDITION	UNIT
1	Ambient Temperature	T_{amb}	+25 +50	$^{\circ}C$
2	Working Voltage	$V_{RM(wkg)}$	See Note $f = 50 / 60Hz$	Vrms
3	Average Output Current	I_O	1.0	A

NOTES

- See Column 3 of Table 1(a).

FIGURE 5 - ELECTRICAL CIRCUIT FOR BURN-IN

Not applicable.



4.8 ENVIRONMENTAL AND ENDURANCE TESTS (CHARTS IV AND V OF ESA/SCC GENERIC SPECIFICATION NO. 5000)

4.8.1 Electrical Measurements on Completion of Environmental Tests

The parameters to be measured on completion of environmental tests are scheduled in Table 2. The measurements shall be performed at $T_{amb} = +22 \pm 3$ °C.

4.8.2 Electrical Measurements at Intermediate Points and on Completion of Endurance Tests

The parameters to be measured at intermediate points and on completion of endurance testing are scheduled in Table 6.

4.8.3 Conditions for Operating Life Tests (Part of Endurance Testing)

The requirements for operating life testing are specified in Section 9 of ESA/SCC Generic Specification No. 5000. The conditions for operating life testing shall be the same as specified in Table 5 for the burn-in test.

4.8.4 Electrical Circuits for Operating Life Tests

The circuit to be used for performance of the operating life test shall be the same as shown in Figure 5 for burn-in.

4.8.5 Conditions for High Temperature Storage Test (Part of Endurance Testing)

The requirements for the high temperature storage test are specified in ESA/SCC Generic Specification No. 5000. The temperature to be applied shall be the maximum storage temperature specified in Table 1(b) of this specification.

**SCC**ESA/SCC Detail Specification
No. 5103/008

PAGE 16

ISSUE 2

TABLE 6 - ELECTRICAL MEASUREMENTS AT INTERMEDIATE POINTS AND ON COMPLETION OF ENDURANCE TESTING

No.	CHARACTERISTICS	SYMBOL	SPEC. AND/OR TEST METHOD	TEST CONDITION	LIMITS		UNIT
					MIN.	MAX.	
1	Forward Voltage	V_F	MIL-STD-750 Method 4011	$I_F = 1.0A$	1.3	-	V
2	Reverse Current	I_R	MIL-STD-750 Method 4016	$V_R = (1) V$	1.0	-	μA
3	Reverse Recovery Time	t_{rr}	MIL-STD-750 Method 4031B	$I_F = 0.5A$ $I_R = 1.0A$ $R_L = 100\Omega$ $I_{RR} = 0.25A$	(2)		nS

NOTES

1. See Column 3 of Table 1(a).
2. See Column 4 of Table 1(a).